

<b>Notice of References Cited</b>	Application/Control No. 10/624,327	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Andy Huynh	Art Unit 2818	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,959,879	09-1999	Koo, Bon-jae	365/145
	B	US-6,066,868	05-2000	Evans, Jr., Joseph T.	257/295
	C	US-6,229,166	05-2001	Kim et al.	257/295
	D	US-6,521,929	02-2003	Ozaki, Tohru	257/295
	E	US-6,602,721	08-2003	Mikawa et al.	438/3
	F	US-6,638,441	10-2003	Chang et al.	216/46
	G	US-6,730,354	05-2004	Gilbert et al.	427/255.32
	H	US-6,730,955	05-2004	Shinohara et al.	257/306
	I	US-6,355,952	03-2002	Yamoto et al.	257/295
	J	US-2003/0132470	07-2003	Joshi et al.	257/295
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.